Sear	ch Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/666,860	TSUKAMOTO ET AL.	
Examiner	Art Unit	
Dah-Wei D. Yuan	1745	

SEARCHED			
Class	Subclass	Date	Examiner
429	94	11/9/2006	DWY
429	623.1	11/9/2006	DWY
429	623.3	11/9/2006	DWY
429	623.5	11/9/2006	DWY
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	11/9/2006	DWY
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